


Introduction

All HardCopy® IV ASICs provide Joint Test Action Group (JTAG) boundary-scan test (BST) circuitry that complies with the IEEE Std. 1149.1 specification. The BST architecture offers the capability to efficiently test components on PCBs with tight lead spacing. Pin connections can be tested without using physical test probes, and functional data can be captured while a device is in normal operation. Boundary-scan cells in a device can force signals onto pins, or capture data from pin or core logic signals. Forced test data is serially shifted into the boundary-scan cells. Captured data is serially shifted out and externally compared to expected results.

A device using the JTAG interface uses four required pins: TDI, TDO, TMS, and TCK, and one optional pin, TRST. The TCK pin has an internal weak pull-down resistor, and the TDI, TMS, and TRST pins have internal weak pull-up resistors. The TDO output pin and all the JTAG input pins are powered by the 2.5-V/3.0-V V_{CCPD} supply of I/O bank 1A.

 For more information about the JTAG pin description, refer to the *JTAG Boundary-Scan Testing in Stratix IV Devices* chapter in volume 1 of the *Stratix IV Device Handbook*.

JTAG Instructions

Table 10–1 shows the JTAG instructions supported in HardCopy IV devices for boundary-scan testing (BST). These 10-bit instructions are also supported in Stratix IV devices. However, HardCopy IV devices do not support the Stratix IV JTAG instructions used for in-circuit reconfiguration (ICR), because HardCopy IV devices do not require configuration.


 For more information about the BST architecture and JTAG instructions supported in Stratix IV devices, refer to the *JTAG Boundary-Scan Testing in Stratix IV Devices* chapter in volume 1 of the *Stratix IV Device Handbook*.

Table 10–1. HardCopy IV JTAG Instructions (Part 1 of 2)

JTAG Instruction	Instruction Code	Description
SAMPLE/PRELOAD	00 0000 0101	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern to be output at the device pins.
EXTTEST (1)	00 0000 1111	Allows the external circuitry and board-level interconnects to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
BYPASS	11 1111 1111	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation.
USERCODE	00 0000 0111	Loads the 32-bit user code into the device identification register and places the register between the TDI and TDO pins, allowing the user code to be serially shifted out of TDO.

Table 10-1. HardCopy IV JTAG Instructions (Part 2 of 2)

JTAG Instruction	Instruction Code	Description
IDCODE	00 0000 0110	Loads the 32-bit ID code into the device identification register and places the register between the TDI and TDO pins, allowing the ID code to be serially shifted out of TDO.
HIGHZ (1)	00 0000 1011	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation while tri-stating all of the I/O pins.
CLAMP (1)	00 0000 1010	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation while holding I/O pins to a state defined by the data in the boundary-scan register.

Note to Table 10-1:

(1) Bus hold and weak pull-up resistor features override the high-impedance state of HIGHZ, CLAMP, and EXTEST.



Similar to Stratix IV devices, HardCopy IV devices support the SignalTap® II Embedded Logic Analyzer, which monitors design operation over a period of time through the JTAG interface. The SignalTap II Embedded Logic Analyzer is a useful feature during the device prototyping phase, but should be removed if not required, after you map the design to a HardCopy IV device. HardCopy IV devices are mask programmed, and the SignalTap II logic cannot be removed after the HardCopy IV device is fabricated.

IDCODE and USERCODE

The IDCODE instruction gives you the ability to shift out a 32-bit identification (ID) code from HardCopy IV devices. ID codes are different in Stratix IV devices and unique for each HardCopy IV device. The ID code can be used to determine the correct device during BST. When the IDCODE instruction is issued, the ID code is loaded into a 32-bit device identification register for shifting out. Table 10-2 shows the ID codes for the HardCopy IV devices.

Table 10-2. 32-Bit HardCopy IV Device IDCODE (Note 1), (2)

Device	IDCODE (32 Bits)			
	Version (4 Bits)	Part Number (16 Bits)	Manufacturer Identity (11 Bits)	LSB (1 Bit)
HC4GX15	0000	0010 0011 0001 0101	000 0110 1110	1
HC4GX25	0000	0010 0011 0010 0101	000 0110 1110	1
HC4GX35	0000	0010 0011 0011 0101	000 0110 1110	1
HC4E25	0000	0010 0110 0010 0101	000 0110 1110	1
HC4E35	0000	0010 0110 0011 0101	000 0110 1110	1

Notes to Table 10-2:

- (1) The MSB is on the left.
 (2) The LSB of IDCODE is always 1.

You can use the USERCODE instruction to shift out a 32-bit user code, which can also be used to uniquely identify the device. Unlike Stratix IV devices, the user code in HardCopy IV devices is mask programmed and cannot be changed after the silicon is fabricated. If the designer does not select a user code, the user code will be mask programmed to default values. When the USERCODE instruction is issued, the 32-bit user code is loaded into the same 32-bit device identification register used for the IDCODE instruction. The user code can then be serially shifted out.

Boundary-Scan Register

The boundary-scan register length for HardCopy IV devices differs from Stratix IV devices. The length also varies for each HardCopy IV device depending on device density and available I/O pin count. Table 10-3 lists the boundary-scan register length for HardCopy IV devices.

Table 10-3. HardCopy IV Boundary-Scan Register Length

Device	Boundary-Scan Register Length
HC4GX15	1146
HC4GX25	1722
HC4GX35	2262
HC4E25	1524
HC4E35	2670

Boundary-Scan Description Language (BSDL) Support

The boundary-scan description language (BSDL), a subset of VHDL, provides a syntax that allows you to describe the features of an IEEE Std. 1149.1 BST-capable device that can be tested.



There are two versions of the BSDL Customizer tool that you can use. The pre-configuration version generates a customized BSDL file for use before the device enters user mode, and the post-configuration version generates a customized BSDL file for use after the device enters user mode.



For more information about BSDL files for IEEE Std. 1149.1-compliant HardCopy IV devices, visit the Altera website at www.altera.com.



BSDL files for IEEE Std. 1149.1-compliant HardCopy IV devices can also be generated using the Quartus software version 8.1 or later. Visit the Altera website at www.altera.com for the procedure to generate the BSDL files using the Quartus II software.



For JTAG timing parameters and values, refer to the *DC and Switching Characteristics of HardCopy IV Devices* chapter in volume 4 of the HardCopy IV Device Handbook.

Document Revision History

Table 10-4 shows the revision history for this chapter.

Table 10-4. Document Revision History

Date and Document Version	Changes Made	Summary of Changes
June 2009, v2.0	<ul style="list-style-type: none">■ Updated “Introduction” on page 10-1.■ Updated “Boundary-Scan Description Language (BSDL) Support” on page 10-3.■ Updated Table 10-2 and Table 10-3.■ Made minor text edits.	—
December 2008, v1.0	Initial release.	—